

REMARKS

In response to an election/restriction requirement presented in an Office Action dated February 12, 2002 in connection with the subject patent application, Applicant hereby elects claims 8-16 for examination. Dependent claims 17-19 have been added without introducing any new matter. In addition, some of the elected claims have been amended editorially as well as to cover the subject matter which the Applicant would like to see examined. Independent claim 8 covers subject matter shown in Figures 2 and 3 which the Office Action labels as being the second species of the invention. New claims 17-19 depend from claim 8 and include additional subject matter shown for example in Figure 1 which was labeled in the Office Action as referring to the first species.

Substantive examination of claims 8-19 to determine their patentability in view of the prior art is respectfully requested.

Respectfully submitted,

BLAKELY SOKOLOFF TAYLOR & ZAFMAN LLP

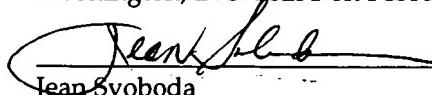


Farzad E. Amini, Reg. No. 42,261

Dated: February 26, 2002
12400 Wilshire Boulevard
Seventh Floor
Los Angeles, California 90025
(310) 207-3800

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231 on February 26, 2002.



Jean Svoboda

VERSION WITH MARKINGS TO SHOW CHANGES MADE

IN THE CLAIMS

Claims 1-7 have been cancelled.

The claims have been amended as follows:

8. (Amended) An imaging system comprising:

an image sensor having a plurality of photocells, the photocells to
~~providing provide~~ sensor signals that are a measure of the intensity of light incident
~~upon the sensor in response to incident light and control signals,~~ the photocells
being part of an integrated circuit (IC) die, the IC die having a first region of
semiconductor material ~~of having~~ a first conductivity type, each of the plurality of
photocells having

a second region of semiconductor material ~~of having~~ a second
conductivity type opposite the first conductivity type and extending over a portion
of the first region, the IC die ~~being configured to~~ permit the incident light to enter a
photosensitive portion of the photocell in the second region,

third and fourth regions of semiconductor material ~~of having~~
the first conductivity type extending over portions of the second region, the third
and fourth regions respectively coupled to first and second electrical contacts, the
first contact to provide a sensor signal of the photocell and the second contact to
provide a signal for detecting saturation of the photocell;

~~control circuitry configured to generate the control signals for controlling the image sensor; and signal processing circuitry for generating image data in response to the sensor signals.~~

9. (Amended) The imaging system of claim 8 wherein the plurality of photocells ~~define are~~ one or more sets of photocells, each set being associated with a respective monitor node, the second contact of each photocell in a set being coupled to the set's respective monitor node, the system ~~being further configured to stop integration in one or more of the sets in response to detecting a predetermined value on the set's respective monitor node.~~

11. (Amended) The imaging system of claim 8 wherein the plurality of photocells are arranged as an array and ~~define are~~ a plurality of sets, each set ~~defined by~~ being a column of the array.

12. (Amended) The imaging system of claim 8 further comprising signal processing circuitry for generating image data in response to the sensor signals, and system controller for controlling the signal processing circuitry.

13. (Amended) The imaging system of claim 8 further comprising optical system ~~configured to receive the incident light to form an image on the image sensor; and~~

communication interface for transferring the image data to an image processing system separate from the imaging system.

14. (Amended) The imaging system of claim 8 wherein the third and fourth regions are formed as implants using a MOS fabrication process in which the second region is formed as a well.

16. (Amended) The imaging system of claim 9 further comprising control circuitry to generate control signals that are coupled to the photocells to control a time interval during which the intensity of the incident light is measured, wherein the control circuitry is to cause causes the set's respective monitor node to be pulled high in response to detecting the predetermined value.

Claims 17-19 have been added.